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# **ECE 448/548 Cyber-System Security**

## **Ring Oscillator PUF**

Dr. F. Gebali

# Outline

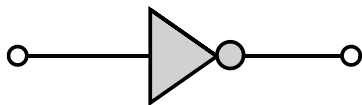
**1** RO

**2** Model

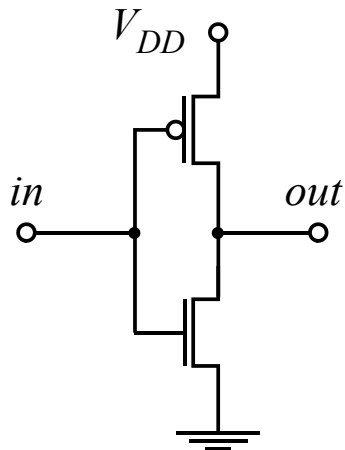
**3** RO Sys

# Ring Oscillator Architecture

# Basic Inverter Structure

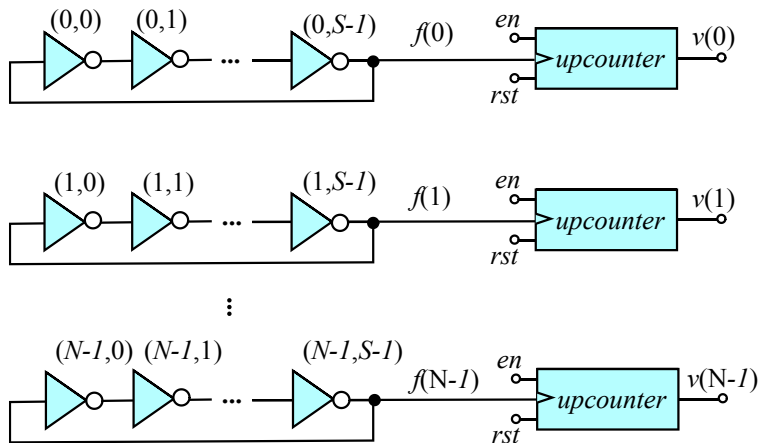


Circuit Symbol

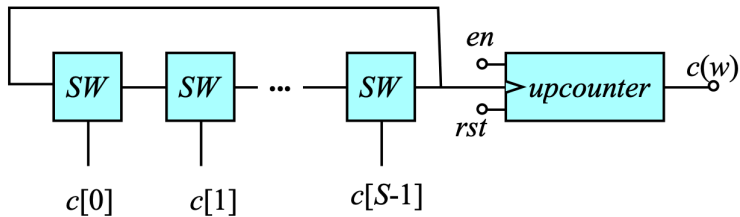


Circuit Diagram

# Ring Oscillator PUF

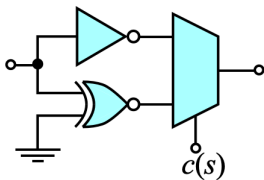


# Configurable Galois Ring Oscillator PUF



(a)

(b)



# RO Oscillation Frequency

$$c = \lfloor T_{obs} f \rfloor \quad \text{number of oscillations}$$

$$= \left\lfloor \frac{T_{obs}}{2T} \right\rfloor$$

$$f = \frac{1}{2T} \text{ Hz} \quad \text{oscillation frequency}$$

$$T = \sum_{s=0}^{S-1} \tau \quad \text{Total gate delay}$$



# RO Encoding

- 1 Choose a row to serve as reference counter  $c_r$
- 2 Choose  $B$  other rows to obtain the  $B$ -bit response
- 3 For row  $i$  we quantize response bit  $b_i$  as

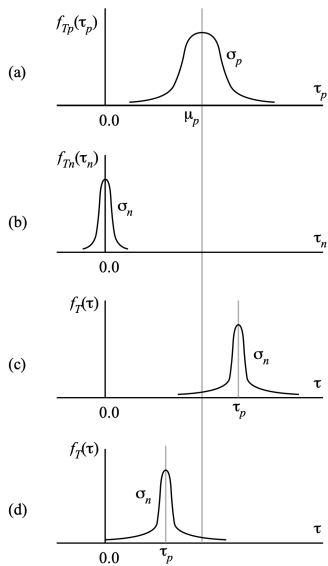
$$b_i = \begin{cases} 0 & \text{when } c_i < c_r \\ 1 & \text{when } c_i \geq c_r \end{cases}$$

# Ring Oscillator PUF Statistical Model

# Ring Oscillator PUF Statistical Model

- 1 Ideal delay of an inverter is  $\tau_i$
- 2 Two sources of noise affecting delay:
  - 1 Slowly-varying random process variations (RPV)
  - 2 Fast-varying random CMOS noise
- 3 CMOS noise is due to
  - 1 Thermal noise represented as an additive white Gaussian noise (AWGN) showing flat spectral distribution
  - 2 Shot noise due to charge carrier flow across semiconductor junctions showing flat spectral distribution
  - 3 Flicker noise due to charge trapping centres in the semiconductor bulk showing  $1/f$  spectral distribution

## RO Statistical Model



# RO Authentication

# Practical RO Authentication

	Hardware		Server		CA
1	Req (ID)	→			
2			Req(ID)	→	
3				←	{c, r}
4			select c		
5			$w = \text{FEC}(r)$		
6			$h = \text{HASH}(r)$		
7		←	$m = \{c, w\}$		
8	$r_1 = \text{PUF}(c)$				
9	$r_2 = \text{Decode}(r_1, w)$				
10	$h_2 = \text{HASH}(r_2)$	→			
11			Compare $h$ & $h_2$		

Numerical Results:  $S = 7$  inverters,  $\mu_p = 1$ ,  $\sigma_p = 0.3$ ,  $SNR_{max} = 30$  dB and  $B = 128$  bits.

